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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/653,327	CHEN, CHIH-WEI	
Examiner	Art Unit	
Anish Sikri	2100	

	SEARCHED					
Class	Subclass	Date	Examiner			
709	223	5/7/2007	AS			
709	225	5/7/2007	AS			
707	10	5/7/2007	AS			
707	8	5/7/2007	AS			

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	5/7/2007	AS			
Inventor name and Assignee search in PALM ExPO and EAST	5/7/2007	AS			
Consulted with Rafael Perez-Gutierrez and George Bugg	5/7/2007	AS			
"709"/\$.ccls. and (((one or single) adj writer) near4 ((several or multiple or many or few) adj readers))	5/7/2007	AS			
((prohibit\$3 or prevent\$3 or inhibit\$3 or deny\$3) with ((multipl\$3 or group or several or many) same (login or access))) and	5/7/2007	AS			
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